

FDH055N15A

N-Channel PowerTrench® MOSFET

150V, 167A, 5.9mΩ

Features

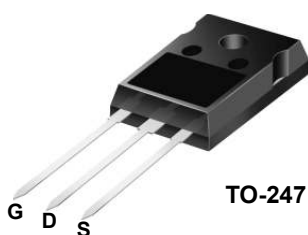
- $R_{DS(on)} = 4.8m\Omega$ (Typ.)@ $V_{GS} = 10V, I_D = 120A$
- Fast Switching Speed
- Low Gate Charge
- High Performance Trench Technology for Extremely Low $R_{DS(on)}$
- High Power and Current Handling Capability
- RoHS Compliant

Description

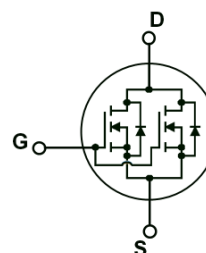
This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Application

- DC to DC Converters
- Synchronous Rectification for Server/Telecom PSU
- Battery Charger
- AC motor drives and Uninterruptible Power Supplies
- Off-line UPS



TO-247



MOSFET Maximum Ratings $T_C = 25^\circ C$ unless otherwise noted

Symbol	Parameter	Ratings	Units
V_{DSS}	Drain to Source Voltage	150	V
V_{GSS}	Gate to Source Voltage	± 20	V
I_D	Drain Current	- Continuous ($T_C = 25^\circ C$, Silicon Limited)	167*
		- Continuous ($T_C = 100^\circ C$, Silicon Limited)	118
		- Continuous ($T_C = 25^\circ C$, Package Limited)	156
I_{DM}	Drain Current	- Pulsed (Note 1)	668
E_{AS}	Single Pulsed Avalanche Energy	(Note 2,6)	835
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0
P_D	Power Dissipation	($T_C = 25^\circ C$)	429
		- Derate above $25^\circ C$	2.86
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +175	$^\circ C$
T_L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^\circ C$

*Calculated continuous current based on maximum allowable junction temperature, Package limitation current is 156A.

Thermal Characteristics

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.35	$^\circ C/W$
$R_{\theta CS}$	Thermal Resistance, Case to Heat Sink (Typical)	0.24	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	40	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDH055N15A	FDH055N15A	TO-247	-	-	30

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
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Off Characteristics

BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	150	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$, Referenced to 25°C	-	0.1	-	$\text{V}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 120\text{V}, V_{GS} = 0\text{V}$ $V_{DS} = 120\text{V}, T_C = 150^\circ\text{C}$	-	-	1 500	μA
I_{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$	-	-	± 100	nA

On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	2.0	-	4.0	V
$R_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{V}, I_D = 120\text{A}$	-	4.8	5.9	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS} = 10\text{V}, I_D = 120\text{A}$ (Note 4)	-	219	-	S

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = 75\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$	-	7100	9445	pF
C_{oss}	Output Capacitance		-	664	885	pF
C_{riss}	Reverse Transfer Capacitance		-	23	-	pF
$C_{oss(er)}$	Energy Related Output Capacitance	$V_{DS} = 75\text{V}, V_{GS} = 0\text{V}$	-	1159	-	pF
$Q_{g(tot)}$	Total Gate Charge at 10V	$V_{DS} = 75\text{V}, I_D = 120\text{A}$ $V_{GS} = 10\text{V}$ (Note 4,5)	-	92	120	nC
Q_{gs}	Gate to Source Gate Charge		-	31	-	nC
Q_{gs2}	Gate Charge Threshold to Plateau		-	15	-	nC
Q_{gd}	Gate to Drain "Miller" Charge		-	16	-	nC
ESR	Equivalent Series Resistance(G-S)		Drain Open	-	1.2	-

Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 75\text{V}, I_D = 120\text{A}$ $V_{GS} = 10\text{V}, R_{GEN} = 4.7\Omega$ (Note 4,5)	-	35	80	ns
t_r	Turn-On Rise Time		-	67	144	ns
$t_{d(off)}$	Turn-Off Delay Time		-	71	152	ns
t_f	Turn-Off Fall Time		-	21	52	ns

Drain-Source Diode Characteristics

I_S	Maximum Continuous Drain to Source Diode Forward Current	-	-	167*	A	
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	668	A	
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_{SD} = 120\text{A}$	-	-	1.25	V
t_{rr}	Reverse Recovery Time	$V_{GS} = 0\text{V}, I_{SD} = 120\text{A}, V_{DS} = 75\text{V}$	-	105	-	ns
Q_{rr}	Reverse Recovery Charge	$di_F/dt = 100\text{A}/\mu\text{s}$ (Note 4)	-	342	-	nC

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Starting $T_J = 25^\circ\text{C}$, $L = 3\text{ mH}$, $I_{AS} = 23.6\text{ A}$.
3. $I_{SD} \leq 120\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$.
4. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
5. Essentially Independent of Operating Temperature Typical Characteristics.
6. Single Pulsed Avalanche Energy per Die.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

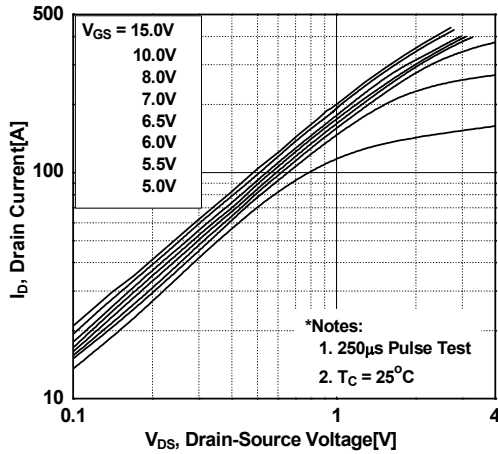


Figure 2. Transfer Characteristics

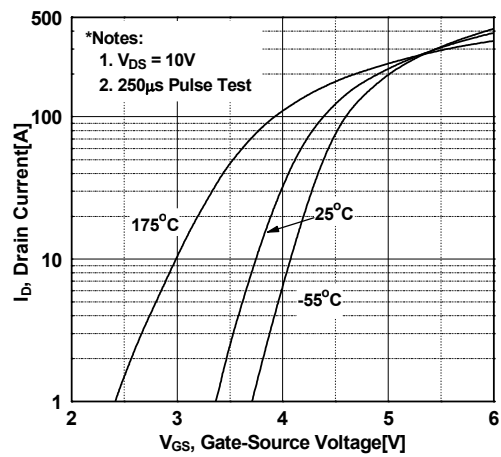


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

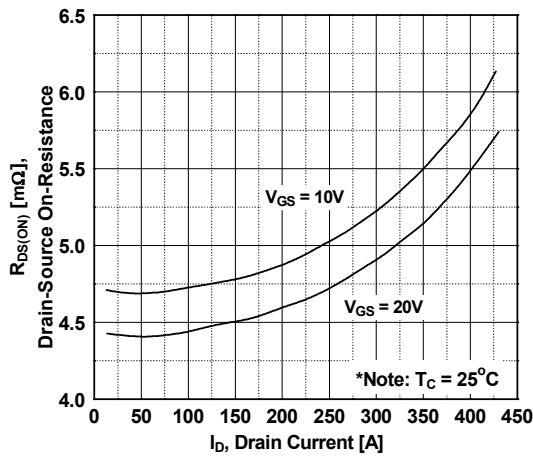


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

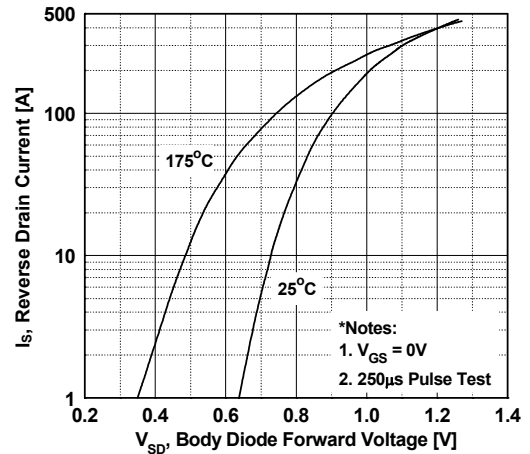


Figure 5. Capacitance Characteristics

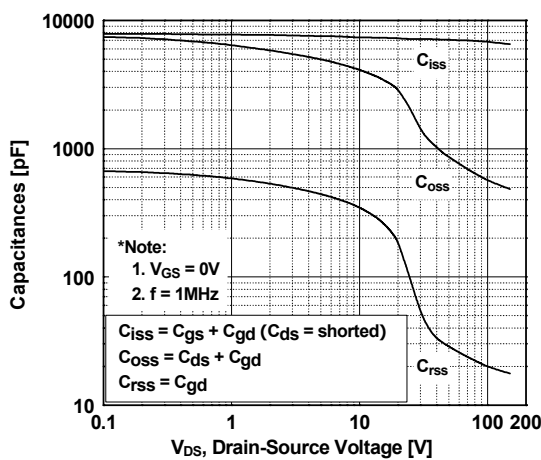
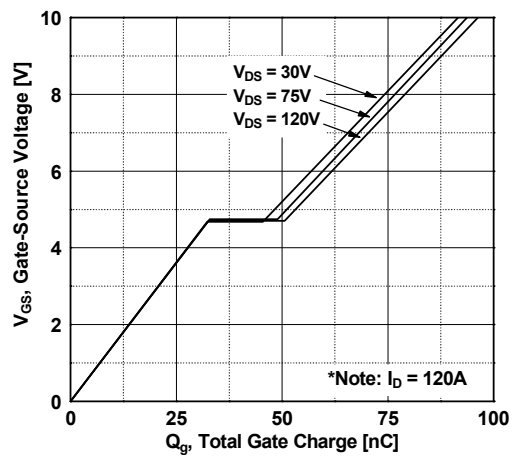


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

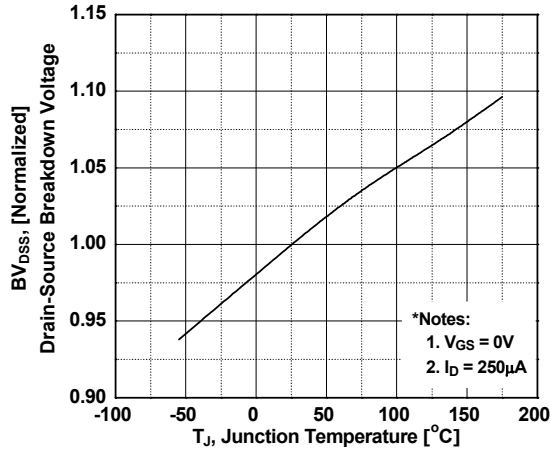


Figure 8. On-Resistance Variation vs. Temperature

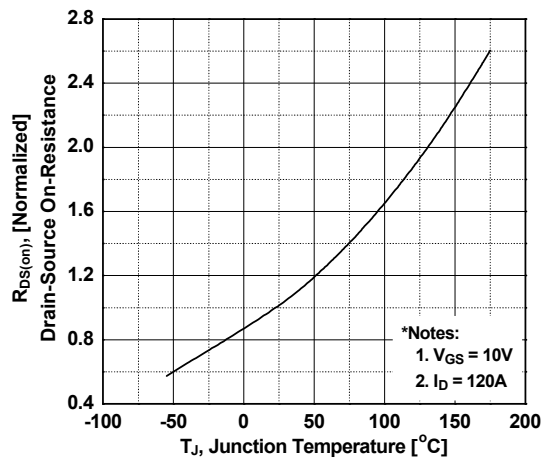


Figure 9. Maximum Safe Operating Area

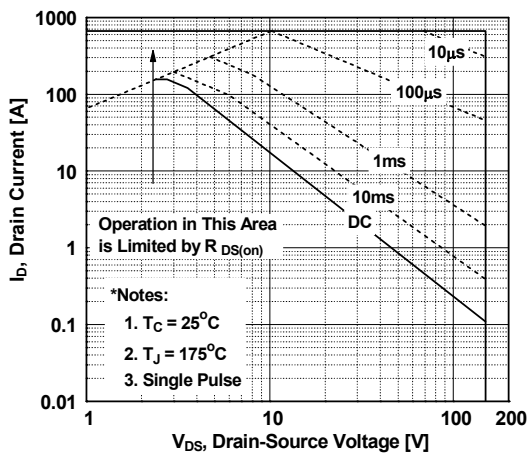


Figure 10. Maximum Drain Current vs. Case Temperature

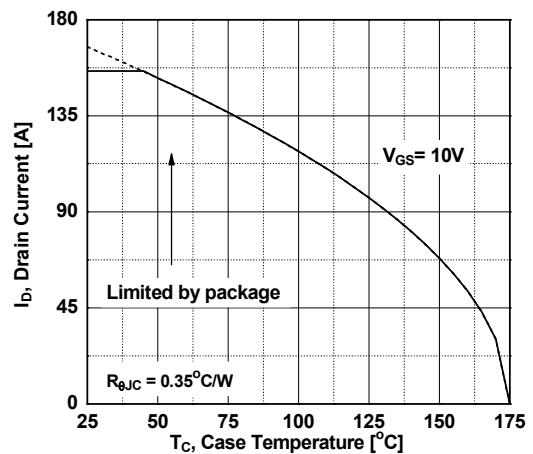
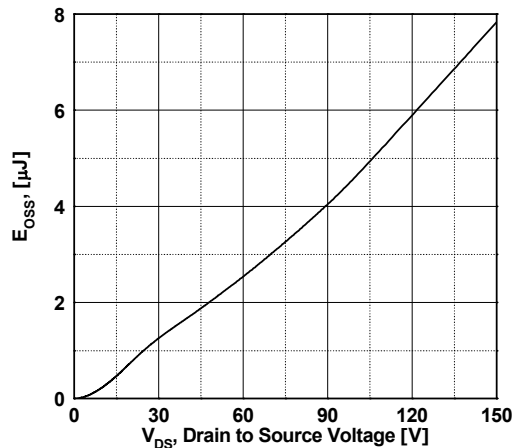
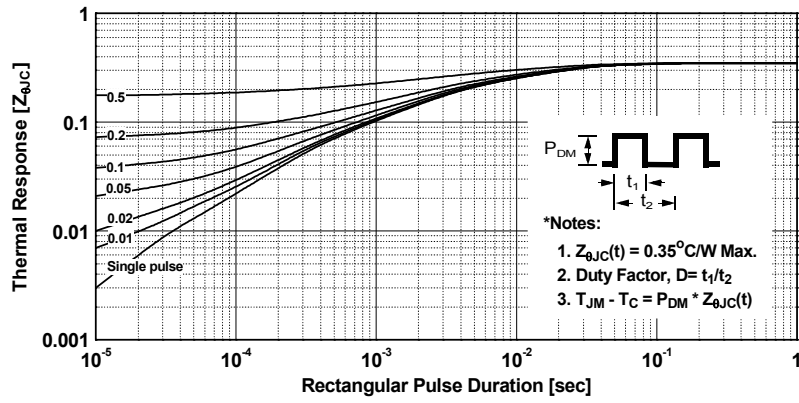


Figure 11. Eoss vs. Drain to Source Voltage

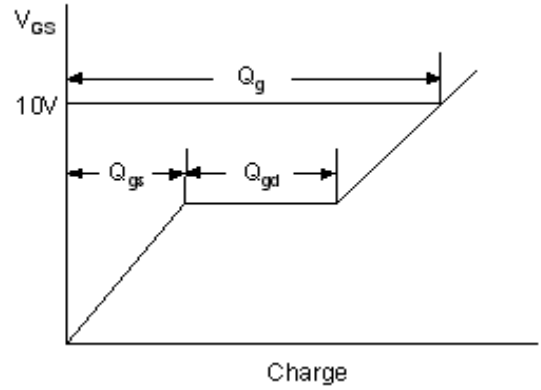
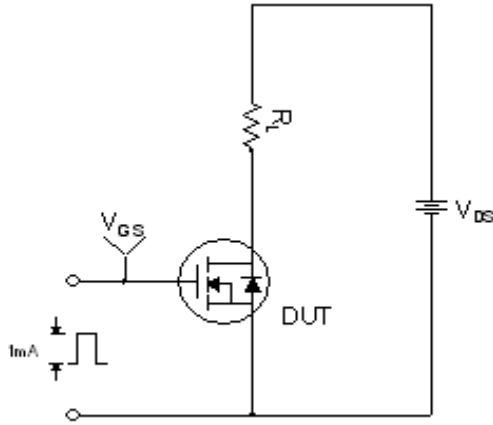


Typical Performance Characteristics (Continued)

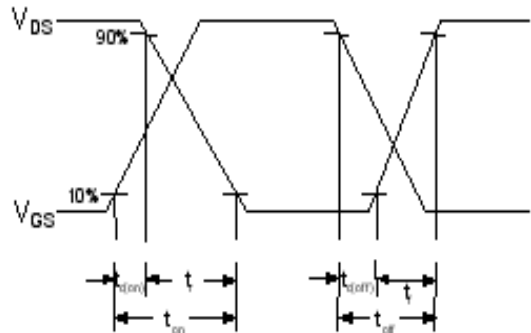
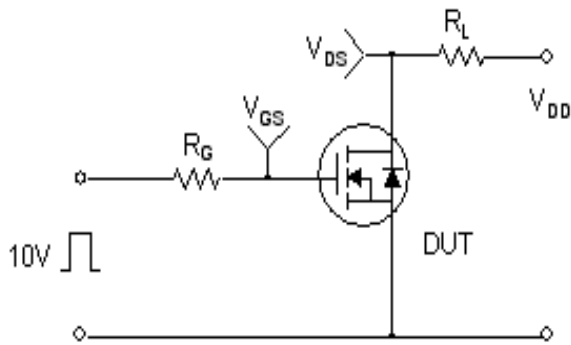
Figure 12. Transient Thermal Response Curve



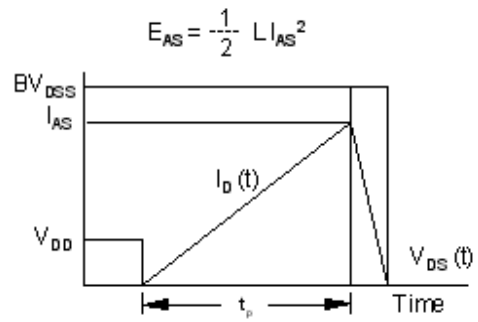
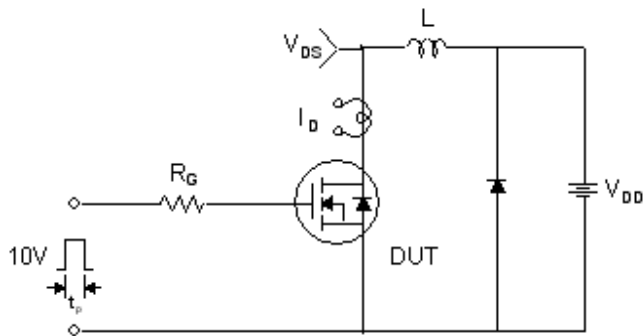
Gate Charge Test Circuit & Waveform



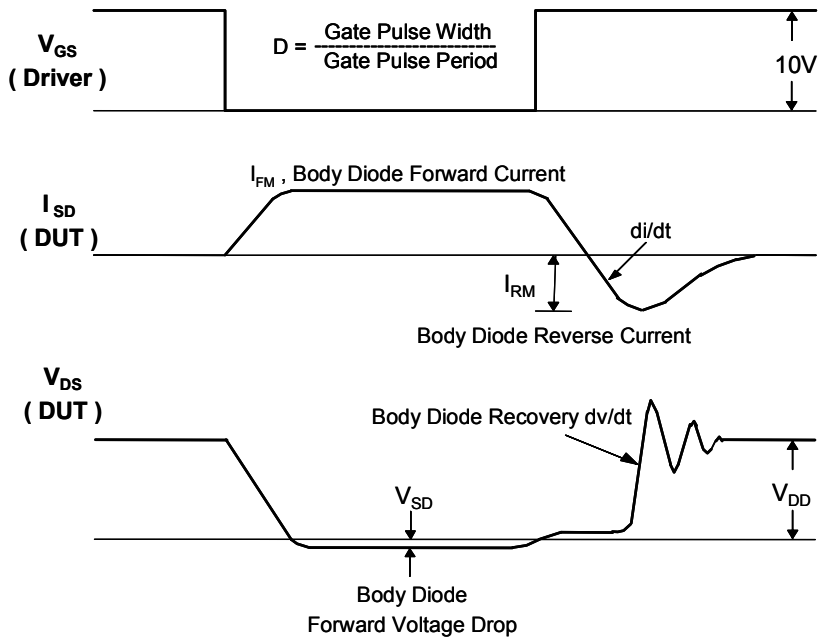
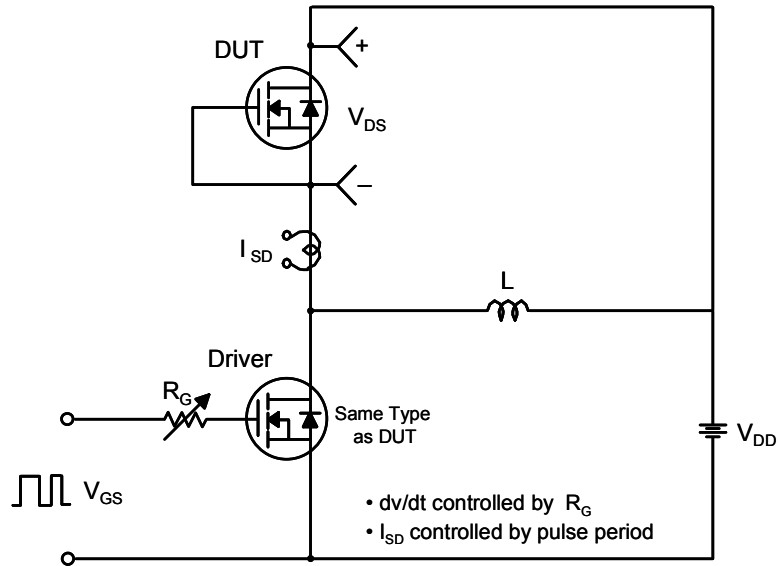
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms








Peak Diode Recovery dv/dt Test Circuit & Waveforms





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